


<b>Search Notes</b> 	<b>Application/Control No.</b> 10574920	<b>Applicant(s)/Patent Under Reexamination</b> MIYAZAWA ET AL.
	<b>Examiner</b> YUN QIAN	<b>Art Unit</b> 4162

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STN and EAST search (PG Pub, USPAT, EPO, JPO, inventor search, consult with Curtis Mayes, 423/text search	9/8/2008	yq

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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